

<b>Search Notes</b> 	<b>Application/Control No.</b> 10/621,708	<b>Applicant(s)/Patent under Reexamination</b> QIAN, XUEJUN
	<b>Examiner</b> Tae H. Yoon	<b>Art Unit</b> 1714

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner